


FORM PTO-1449 LIST OF PATENTS AND OTHER INFORMATION FOR APPLICANT'S DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO. 249/118	SERIAL NO. To Be Determined
	APPLICANT: O'Gorman, et al.	
	FILING DATE: April 5, 2002	GROUP: To Be Determined

U.S. PATENT DOCUMENTS							
EXAMINE R INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
AWC	AA	6,049,620	04/11/00	Dickinson, et al.	382	124	05/13/97
AWC	AB	6,016,355	01/18/00	Dickinson, et al.	382	124	12/15/95
AWC	AC	5,719,950	02/17/98	Osten, et al.	382	115	08/30/95
AWC	AD	5,587,533	12/24/96	Schneider, et al.	73	614	01/27/95

FOREIGN PATENT DOCUMENTS								
EXAMINE R INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATIO YES N NO	
AWC	AE	10290796	04/11/98	Japan	A61B	5/117	X	
AWC	AF	03053385	03/07/91	Japan	G06F	15/62	X	
AWC	AG	0 372 748 A2, A3	06/13/90	EPO	A61B	5/117	X	
AWC	AH	01/59690 A1	08/16/01	WO	G06K	9/00	X	
AWC	AI	01/06448 A1	01/25/01	WO	G06K	9/00	X	
AWC	AJ	01/06447 A1	01/25/01	WO	G06K	9/00	X	
AWC	AK	01/06445 A1	01/25/01	WO	G06K	9/00	X	
AWC	AL	00/65770	11/02/00	WO	H04L	9/30-32	X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)		
AWC	AM	Otsu, "A Threshold Selection Method From Gray-Level Histograms," <i>IEEE Transactions on Systems, Man, and Cybernetics</i> , Vol. SMC-9 (1):62-66 (January 1979)
AWC	AN	Lam, et al., "Thinning Methodologies - A Comprehensive Survey," <i>IEEE Transactions on Pattern Analysis And Machine Intelligence</i> , Vol. 14 (9): 869-885 (September 1992)

EXAMINER: 	DATE CONSIDERED: 3/22/05
EXAMINER: Please initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered; and include a copy of this form with next communication to applicant. Thank you.	